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Form 1449 (Modified)	Atty Docket No: ROXIP262	U.S. 09/378,398
Information Disclosur	re Applicants:	02/07/03/0
Statement By Applica	nt TEO, Patrick Filing Date:	Group:
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**U.S. Patent Documents** 

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Initial	No.	Patent No.	Date	Patentee	Class	class
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Foreign Patent or Published Foreign Patent Application

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m	R	"Casio QV700 Digital Camera & DP-8000 Digital Photo Printer", Joe Farace,
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an	S	"Round Shot", 4pp.
w	T	"Casio QV-200, QV-700", James Karney, PC Magazine, 2pp., 2-10-98.
m	U	"Round Shot Super 35 13.5.96". Bob Erickson, 1 pg.
~	V	"Casio Adds New Camera To Its Lineup", Kelly Ryer, MacWeek, Vol. 11,
lu		issue 38, 1 pg., October 2, 1997.
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Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Eorm 1449 (Modified)

Information Disclosure Statement By Applicant

(Use Several Sheets if Necessary)

Attorney Docket No:

ROXIP262

U.S.

09/378/398

Applicant: TEO, Patrick

Filing Date: August 20, 1999

Group: 2613

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m	UU	US 5 963 213		Guedalia et al.			

Foreign Patent or Published Foreign Patent Application

Examiner No.		Document	Publication	Country or		Sub-	Translation	
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**Other Documents** 

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